



IFW  
Analog.7335

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**APPLICANT:** Nevin et al. **GROUP:** 2823  
**SERIAL NO:** 10/699,503 **EXAMINER:** Hsien Ming Lee  
**FILED:** 10/31/03  
**FOR:** METHOD FOR FORMING A FILLED TRENCH IN A SEMICONDUCTOR LAYER OF A SEMICONDUCTOR SUBSTRATE, AND A SEMICONDUCTOR SUBSTRATE WITH A SEMICONDUCTOR LAYER HAVING A FILLED TRENCH THEREIN

Mail Stop Amendment  
Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450  
Sir:

**INFORMATION DISCLOSURE STATEMENT**

In compliance with 37 C.F.R. §§1.56, 1.97, and 1.98, Applicant submits copies of the foreign documents listed on the attached Form PTO-1449.

The listed documents were recently cited in a related PCT application, and a copy of the International Search Report is being submitted herewith for purposes of convenience.

The Commissioner is authorized to charge Deposit Order Account No. 19-0079 for any further fee that is required.

Respectfully submitted,

Matthew E. Connors  
Registration No. 33,298  
Gauthier & Connors LLP  
225 Franklin Street, Suite 3300  
Boston, Massachusetts 02110  
Telephone: (617) 426-9180  
Extension 112

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to Mail Stop Amendment, Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Deborah M. Costello

10-17-05  
Date

FORM PTO-1449  
(Rev. 5/92)GAUTHIER & CONNORS LLP  
225 Franklin Street, Boston, MA 02110  
Telephone: (617) 426-9180

ATTORNEY DOCKET NO. 7335

SERIAL NO. 10/699,503

APPLICANT: Nevin et al.

GROUP: 2823

FILING DATE: 10/31/03

EXAMINER: Hsien Ming Lee

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT****U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	20010045614	11/29/01	Begley et al			4/1/99
	AB	20020121673	9/5/02	Jono et al.			11/8/01
	AC	20010023134	9/20/01	Akatsu et al.			3/31/98
	AD	4,639,288	1/27/87	Price et al.			11/5/84
	AE	4,656,730	4/14/87	Lynch et al.			11/23/84
	AF	6,198,150	3/6/01	Gelzinis			3/6/01
	AG	4,839,306	6/13/89	Wakamatsu			3/23/88
	AH	6,627,514	9/30/03	Park et al.			11/10/00
	AI						

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AJ	0 048 175	9/16/81	EPO			Yes
	AK						
	AL						

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
	AM	
	AN	
	AO	

EXAMINER

DATE CONSIDERED

EXAMINER:

Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.